

**Search Notes**

Application/Control No.

10/525,683

Examiner

Ren L. Yan

Applicant(s)/Patent under  
Reexamination

LORIG ET AL.

Art Unit

2854

**SEARCHED**

Class	Subclass	Date	Examiner
101	216 217	4/26/07	RY
	375		
	376		
	382.1		
	383		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR